

# Engineering the band structure of $\text{Hg}_{1-x}(\text{Cd}|\text{Mn})_x\text{Te}$ with x-Cd or x-Mn component based two- and three-dimensional topological insulator



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## Abstract

Since the HgTe materials were discovered as a material with topological insulator properties in two cases: so called three dimensional (3D) as well as two dimensional (2D) topological insulator (for 75nm wide and about 6.4nm wide QW HgTe films respectively for 3D and 2D cases) many papers were devoted to investigation concerning the electronics, optics and many other different properties for such structures. All of this activity, beside from the pure science point of view, were caused to know better the properties from the point of view of the possible applications region for such new state of matter based on HgTe compounds. In this paper however we present the properties of much more complex structures like A<sub>1-x</sub>B<sub>x</sub>C solid solutions based on HgTe (A and C) materials with different than 0 x- Cd and Mn compounds (B - part in the Hg<sub>1-x</sub>B<sub>x</sub>Te). Beside the differences caused by influence of Cd and Mn compounds into the HgTe materials the additional physical, structural and geometry factors are taken into account from the point of view of the possible properties of such modified HgTe-based compounds. To show how all of these properties can be changed for such complex structures comparing with the HgTe pure materials we all our investigation presents here is based on the very well known theoretical eight band kp model which is a key to understand all of the electronic, optical and many different properties flowing from this state of matter. Additional magnetic field and Landau level spectroscopy can give the information about the quality of the TI states for investigated Hg<sub>1-x</sub>B<sub>x</sub>Te solid solutions. Together with the physical and external conditions such as bulk inversion asymmetry (BIA), structural inversion asymmetry (SIA) and interface inversion asymmetry (IIA) which plays a critical role in the TI cases the band structure modifications are also taken into account in the presented paper from the point of view of the modifications parameters comparing to that obtained for 3D as well as 2D materials pure HgTe films.

## Theory

$$H_0 = \begin{pmatrix} T & 0 & \frac{-1}{\sqrt{2}}Pk_+ & \sqrt{\frac{2}{3}}Pk_z & \frac{1}{\sqrt{6}}Pk_- & 0 & \frac{-1}{\sqrt{3}}Pk_z & \frac{-1}{\sqrt{3}}Pk_- \\ 0 & T & 0 & \frac{-1}{\sqrt{6}}Pk_+ & \sqrt{\frac{2}{3}}Pk_z & \frac{1}{\sqrt{2}}Pk_- & \frac{-1}{\sqrt{3}}Pk_+ & \frac{1}{\sqrt{3}}Pk_z \\ \frac{-1}{\sqrt{2}}k_-P & 0 & U+V & -\bar{S}_- & R & 0 & \frac{1}{\sqrt{2}}\bar{S}_- & -\sqrt{2}R \\ \sqrt{\frac{2}{3}}k_zP & \frac{-1}{\sqrt{6}}k_-P & -\bar{S}_+^\dagger & U-V & C & R & \sqrt{2}V & -\sqrt{\frac{3}{2}}\bar{S}_- \\ \frac{1}{\sqrt{6}}k_+P & \sqrt{\frac{2}{3}}k_zP & R^\dagger & C^\dagger & U-V & \bar{S}_+^\dagger & -\sqrt{\frac{3}{2}}\bar{S}_+ & -\sqrt{2}V \\ 0 & \frac{1}{\sqrt{2}}k_+P & 0 & R^\dagger & \bar{S}_+ & U+V & \sqrt{2}R^\dagger & \frac{1}{\sqrt{2}}\bar{S}_+ \\ \frac{-1}{\sqrt{3}}k_zP & \frac{-1}{\sqrt{3}}k_-P & \frac{1}{\sqrt{2}}\bar{S}_+^\dagger & \sqrt{2}V & -\sqrt{\frac{3}{2}}\bar{S}_+^\dagger & \sqrt{2}R & U-\Delta & C \\ \frac{-1}{\sqrt{3}}k_+P & \frac{1}{\sqrt{3}}k_zP & -\sqrt{2}R^\dagger & -\sqrt{\frac{3}{2}}\bar{S}_+^\dagger & -\sqrt{2}V & \frac{1}{\sqrt{2}}\bar{S}_+^\dagger & C^\dagger & U-\Delta \end{pmatrix}$$

$$k_{||}^2 = k_x^2 + k_y^2, \quad k_{\pm} = k_x \pm ik_y, \quad k_z = -i\partial/\partial z,$$

$$T = E_c(z) + \frac{\hbar^2}{2m_0}[(2F+1)k_{||}^2 + k_z(2F+1)k_z],$$

$$U = E_v(z) - \frac{\hbar^2}{2m_0}(\gamma_1 k_{||}^2 + k_z\gamma_2 k_z),$$

$$V = -\frac{\hbar^2}{2m_0}(\gamma_2 k_{||}^2 - 2k_z\gamma_2 k_z),$$

$$R = -\frac{\hbar^2}{2m_0}\sqrt{3}(\mu k_{\pm}^2 - \gamma k_z^2),$$

$$\bar{S}_{\pm} = -\frac{\hbar^2}{2m_0}\sqrt{3}k_{\pm}(\{\gamma_3, k_z\} + [\kappa, k_z]),$$

$$\bar{S}_{\pm} = -\frac{\hbar^2}{2m_0}\sqrt{3}k_{\pm}(\{\gamma_3, k_z\} - \frac{1}{3}[\kappa, k_z]),$$

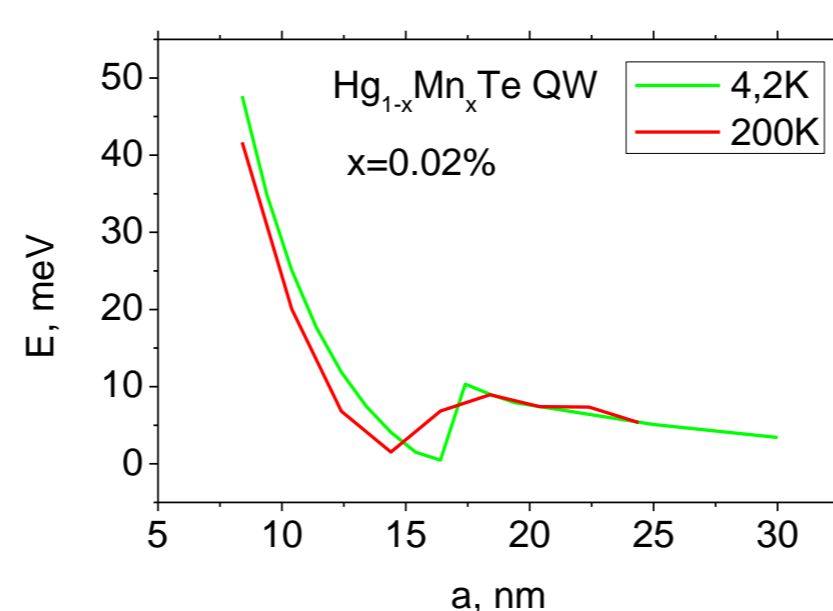
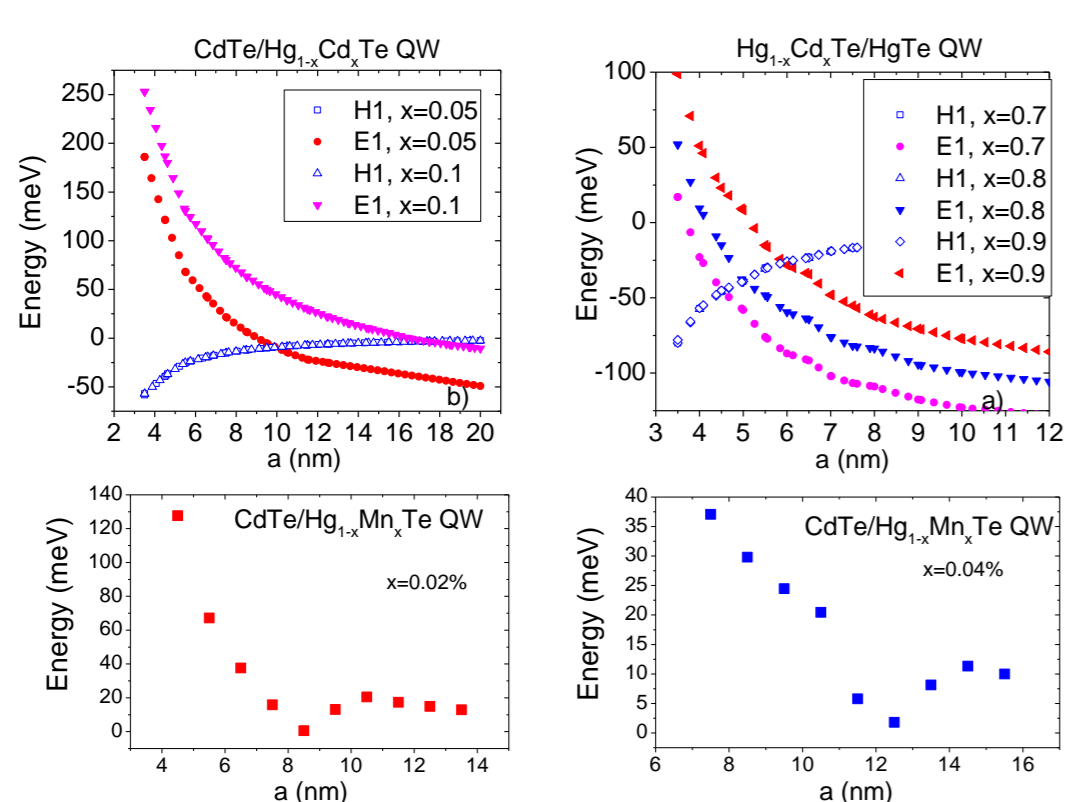
$$C = \frac{\hbar^2}{m_0}k_{\pm}[\kappa, k_z].$$

TABLE I. Band structure parameters of HgTe and CdTe (Refs. 27, 28).

	HgTe	CdTe	HgTe	CdTe
$E_g$	-0.303 eV	1.606 eV	$C$	-3.83 eV -4.06 eV
$E_v$	0	-570 meV	$a$	0 -0.7 eV
$\Delta$	1.08 eV	0.91 eV	$b$	-1.5 eV -1.17 eV
$E_p$	18.8 eV	18.8 eV	$d$	-2.08 eV -3.2 eV
$F$	0	-0.09	$C_{11}$	53.6 GPa 53.6 GPa
$\gamma_1$	4.1	1.47	$C_{12}$	36.6 GPa 37.0 GPa
$\gamma_2$	0.5	-0.28	$C_{44}$	21.2 GPa 19.9 GPa
$\gamma_3$	1.3	0.03		
$\kappa$	-0.4	-1.31		

## 3D, 2D Hg(Cd|Mn)Te

$$(H_0 + H_{BP} + V(z))\Psi(z) = E\Psi(z)$$



## 3D, 2D HgCdTe with asymmetry

$$(H_0 + H_{BP} + H_{SIA} + H_{BIA} + H_{IIA} + V(z))\Psi(z) = E\Psi(z)$$

